


<b>Search Notes</b>  	<b>Application/Control No.</b>  10781415	<b>Applicant(s)/Patent Under Reexamination</b>  BAYON, PAUL WILLIAM
	<b>Examiner</b>  Marandi, James R	<b>Art Unit</b>  4157

SEARCHED			
Class	Subclass	Date	Examiner
725	38, 46	10/24/07	JRM
345	327	10/24/07	JRM
348	731	11/28/07	JRM

SEARCH NOTES			
Search Notes		Date	Examiner
East		10/24/07	JRM
IEEE, ACM		10/24/07	JRM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner